

Notice of References Cited	Application/Control No. 10/727,746	Applicant(s)/Patent Under Reexamination LIU, HENG	
	Examiner Ram N. Kackar	Art Unit 1763	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0005886	01-2003	Park et al.	118/725
*	B	US-5,334,277	08-1994	Nakamura, Shuji	117/102
*	C	US-2003/0005958	01-2003	Rocha-Alvarez et al.	137/118.01
*	D	US-2002/0054745	05-2002	Van de Walle et al.	385/131
*	E	US-4,812,331	03-1989	Hirooka et al.	427/255.26
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.